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Intel - 5AGXMA7G4F31C4N Datasheet



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	11460
Number of Logic Elements/Cells	242000
Total RAM Bits	15470592
Number of I/O	384
Number of Gates	-
Voltage - Supply	1.07V ~ 1.13V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	896-BBGA, FCBGA
Supplier Device Package	896-FBGA (31x31)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5agxma7g4f31c4n

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



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Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications

1/O Standard	VII	_{-(DC)} (V)	V _{IH(D}	_{C)} (V)	V _{IL(AC)} (V)	V _{IH(AC)} (V)	V _{OL} (V)	V _{OH} (V)	I _{OL} ⁽¹⁴⁾	(14)(mA)
	Min	Max	Min	Мах	Max	Min	Мах	Min	(mA)	IOH. (IIIIM)
SSTL-2 Class I	-0.3	V _{REF} - 0.15	V _{REF} + 0.15	$V_{CCIO} + 0.3$	V _{REF} - 0.31	V _{REF} + 0.31	V _{TT} – 0.608	V _{TT} + 0.608	8.1	-8.1
SSTL-2 Class II	-0.3	V _{REF} – 0.15	V _{REF} + 0.15	$V_{CCIO} + 0.3$	V _{REF} – 0.31	V _{REF} + 0.31	V _{TT} – 0.81	V _{TT} + 0.81	16.2	-16.2
SSTL-18 Class I	-0.3	V _{REF} - 0.125	V _{REF} + 0.125	$V_{CCIO} + 0.3$	V _{REF} – 0.25	V _{REF} + 0.25	V _{TT} – 0.603	V _{TT} + 0.603	6.7	-6.7
SSTL-18 Class II	-0.3	V _{REF} – 0.125	V _{REF} + 0.125	$V_{CCIO} + 0.3$	V _{REF} – 0.25	V _{REF} + 0.25	0.28	V _{CCIO} – 0.28	13.4	-13.4
SSTL-15 Class I	—	V _{REF} – 0.1	$V_{REF} + 0.1$	_	V _{REF} - 0.175	V _{REF} + 0.175	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	8	-8
SSTL-15 Class II	—	V _{REF} – 0.1	$V_{REF} + 0.1$	—	V _{REF} - 0.175	V _{REF} + 0.175	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	16	-16
SSTL-135	—	V _{REF} - 0.09	$V_{REF} + 0.09$	_	V _{REF} - 0.16	$V_{REF} + 0.16$	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$		
SSTL-125	—	V _{REF} - 0.85	$V_{REF} + 0.85$	—	V _{REF} - 0.15	$V_{REF} + 0.15$	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$		
HSTL-18 Class I	_	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.2	V _{REF} + 0.2	0.4	V _{CCIO} – 0.4	8	-8
HSTL-18 Class II	_	V _{REF} – 0.1	V _{REF} + 0.1	_	V _{REF} – 0.2	$V_{REF} + 0.2$	0.4	V _{CCIO} – 0.4	16	-16
HSTL-15 Class I	_	V _{REF} – 0.1	$V_{REF} + 0.1$		V _{REF} – 0.2	V _{REF} + 0.2	0.4	$V_{CCIO} - 0.4$	8	-8



⁽¹⁴⁾ To meet the I_{OL} and I_{OH} specifications, you must set the current strength settings accordingly. For example, to meet the SSTL15CI specification (8 mA), you should set the current strength settings to 8 mA. Setting at lower current strength may not meet the I_{OL} and I_{OH} specifications in the datasheet.

Transceiver Specifications for Arria V GT and ST Devices

Table 1-26: Reference Clock Specifications	for Arria V GT and ST Devices
--	-------------------------------

Symbol/Description	Condition	Tran	sceiver Speed Gra	Unit	
Symbol/Description	Condition	Min	Тур	Мах	Onic
Supported I/O standards	1.2 V PCML, 1.4 VPCML,	1.5 V PCML, 2.5	V PCML, Differe	ential LVPECL ⁽⁴⁰⁾	, HCSL, and LVDS
Input frequency from REFCLK input pins	_	27		710	MHz
Rise time	Measure at ±60 mV of differential signal ⁽⁴¹⁾	_		400	ps
Fall time	Measure at ±60 mV of differential signal ⁽⁴¹⁾			400	ps
Duty cycle	_	45		55	%
Peak-to-peak differential input voltage	—	200		300 ⁽⁴²⁾ /2000	mV
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30		33	kHz
Spread-spectrum downspread	PCIe		0 to -0.5%		_
On-chip termination resistors	—		100		Ω
V _{ICM} (AC coupled)	—		1.2		V
V _{ICM} (DC coupled)	HCSL I/O standard for the PCIe reference clock	250		550	mV



⁽⁴⁰⁾ Differential LVPECL signal levels must comply to the minimum and maximum peak-to-peak differential input voltage specified in this table.

REFCLK performance requires to meet transmitter REFCLK phase noise specification. (41)

⁽⁴²⁾ The maximum peak-to peak differential input voltage of 300 mV is allowed for DC coupled link.

Table 1-38: Memory Block Performance Specifications for Arria V Devices

Momory	Mada	Resources Used		Performance			Unit
Memory	Mode	ALUTs	Memory	-I3, -C4	-I5, -C5	-C6	Ont
	Single port, all supported widths	0	1	500	450	400	MHz
	Simple dual-port, all supported widths	0	1	500	450	400	MHz
MLAB	Simple dual-port with read and write at the same address	0	1	400	350	300	MHz
	ROM, all supported width	_		500	450	400	MHz
	Single-port, all supported widths	0	1	400	350	285	MHz
	Simple dual-port, all supported widths	0	1	400	350	285	MHz
M10K Block	Simple dual-port with the read-during- write option set to Old Data , all supported widths	0	1	315	275	240	MHz
	True dual port, all supported widths	0	1	400	350	285	MHz
	ROM, all supported widths	0	1	400	350	285	MHz

Internal Temperature Sensing Diode Specifications

Table 1-39: Internal Temperature Sensing Diode Specifications for Arria V Devices

Temperature Range	Accuracy	Offset Calibrated Option	Sampling Rate	Conversion Time	Resolution	Minimum Resolution with no Missing Codes
-40 to 100°C	±8°C	No	1 MHz	< 100 ms	8 bits	8 bits

Periphery Performance

This section describes the periphery performance, high-speed I/O, and external memory interface.

Actual achievable frequency depends on design and system specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.



Figure 1-10: SPI Slave Timing Diagram



Related Information

SPI Controller, Arria V Hard Processor System Technical Reference Manual

Provides more information about rx_sample_delay.

SD/MMC Timing Characteristics

Table 1-54: Secure Digital (SD)/MultiMediaCard (MMC) Timing Requirements for Arria V Devices

After power up or cold reset, the Boot ROM uses drvsel = 3 and smplsel = 0 to execute the code. At the same time, the SD/MMC controller enters the Identification Phase followed by the Data Phase. During this time, the value of interface output clock SDMMC_CLK_OUT changes from a maximum of 400 kHz (Identification Phase) up to a maximum of 12.5 MHz (Data Phase), depending on the internal reference clock SDMMC_CLK and the CSEL setting. The value of SDMMC_CLK is based on the external oscillator frequency and has a maximum value of 50 MHz.



Table 1-57: RGMII RX Timing Requirements for Arria V Devices

Symbol	Description	Min	Тур	Unit
T _{clk} (1000Base-T)	RX_CLK clock period		8	ns
T _{clk} (100Base-T)	RX_CLK clock period		40	ns
T _{clk} (10Base-T)	RX_CLK clock period		400	ns
T _{su}	RX_D/RX_CTL setup time	1		ns
T _h	RX_D/RX_CTL hold time	1		ns

Figure 1-14: RGMII RX Timing Diagram



Table 1-58: Management Data Input/Output (MDIO) Timing Requirements for Arria V Devices

Symbol	Description	Min	Тур	Мах	Unit
T _{clk}	MDC clock period	—	400	_	ns
T _d	MDC to MDIO output data delay	10		20	ns
T _s	Setup time for MDIO data	10	_		ns
T _h	Hold time for MDIO data	0			ns



Figure 1-16: I²C Timing Diagram



NAND Timing Characteristics

Table 1-60: NAND ONFI 1.0 Timing Requirements for Arria V Devices

The NAND controller supports Open NAND FLASH Interface (ONFI) 1.0 Mode 5 timing as well as legacy NAND devices. This table lists the requirements for ONFI 1.0 mode 5 timing. The HPS NAND controller can meet this timing by programming the c4 output of the main HPS PLL and timing registers provided in the NAND controller.

Symbol	Description	Min	Max	Unit
T _{wp} ⁽⁸⁹⁾	Write enable pulse width	10	—	ns
T _{wh} ⁽⁸⁹⁾	Write enable hold time	7		ns
T _{rp} ⁽⁸⁹⁾	Read enable pulse width	10		ns
T _{reh} ⁽⁸⁹⁾	Read enable hold time	7		ns
T _{clesu} ⁽⁸⁹⁾	Command latch enable to write enable setup time	10		ns
T _{cleh} ⁽⁸⁹⁾	Command latch enable to write enable hold time	5		ns
T _{cesu} ⁽⁸⁹⁾	Chip enable to write enable setup time	15		ns
T _{ceh} ⁽⁸⁹⁾	Chip enable to write enable hold time	5		ns
T _{alesu} ⁽⁸⁹⁾	Address latch enable to write enable setup time	10		ns
T _{aleh} ⁽⁸⁹⁾	Address latch enable to write enable hold time	5		ns
T _{dsu} ⁽⁸⁹⁾	Data to write enable setup time	10		ns

⁽⁸⁹⁾ Timing of the NAND interface is controlled through the NAND configuration registers.



Figure 1-19: NAND Data Write Timing Diagram





1-76 FPGA JTAG Configuration Timing

POR Delay	Minimum	Maximum	Unit
Standard	100	300	ms

Related Information

MSEL Pin Settings

Provides more information about POR delay based on MSEL pin settings for each configuration scheme.

FPGA JTAG Configuration Timing

Table 1-64: FPGA JTAG Timing Parameters and Values for Arria V Devices

Symbol	Description	Min	Max	Unit
t _{JCP}	TCK clock period	30, 167 ⁽⁹²⁾		ns
t _{JCH}	TCK clock high time	14		ns
t _{JCL}	TCK clock low time	14		ns
t _{JPSU (TDI)}	TDI JTAG port setup time	2		ns
t _{JPSU (TMS)}	TMS JTAG port setup time	3		ns
t _{JPH}	JTAG port hold time	5		ns
t _{JPCO}	JTAG port clock to output		12 ⁽⁹³⁾	ns
t _{JPZX}	JTAG port high impedance to valid output		14 ⁽⁹³⁾	ns
t _{JPXZ}	JTAG port valid output to high impedance		14 ⁽⁹³⁾	ns



⁽⁹²⁾ The minimum TCK clock period is 167 ns if V_{CCBAT} is within the range 1.2 V – 1.5 V when you perform the volatile key programming.

⁽⁹³⁾ A 1-ns adder is required for each VCCIO voltage step down from 3.0 V. For example, tJPCO= 13 ns if VCCIO of the TDO I/O bank = 2.5 V, or 14 ns if it equals 1.8 V.

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	Symbol	Parameter	Typical	Unit
		Rising and/or falling edge delay	0 (default)	ps
D _{OUTBUF}	50		ps	
	100		ps	
			150	ps

Glossary

Table 1-78: Glossary

Term	Definition	
Differential I/O standards	Receiver Input Waveforms	
	Single-Ended Waveform	Positive Channel (p) = V_{IH} Negative Channel (n) = V_{IL}
		Ground
	Differential Waveform	
		p - n = 0 V



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Bus Hold Specifications

Table 2-9: Bus Hold Parameters for Arria V GZ Devices

			V _{CCIO}										
Parameter	Symbol	Conditions	1.2	2 V	1.5	5 V	1.8	3 V	2.5	5 V	3.0	V	Unit
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I _{SUSL}	V _{IN} > V _{IL} (maximum)	22.5	_	25.0	_	30.0		50.0	_	70.0	_	μΑ
High sustaining current	I _{SUSH}	V _{IN} < V _{IH} (minimum)	-22.5	_	-25.0	_	-30.0	_	-50.0	_	-70.0	_	μΑ
Low overdrive current	I _{ODL}	$0V < V_{IN} < V_{CCIO}$	_	120	_	160	_	200	_	300	_	500	μΑ
High overdrive current	I _{ODH}	$0V < V_{IN} < V_{CCIO}$	—	-120	_	-160	_	-200		-300	_	-500	μΑ
Bus-hold trip point	V _{TRIP}		0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

On-Chip Termination (OCT) Specifications

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block.

Table 2-10: OCT Calibration Accuracy Specifications for Arria V GZ Devices

OCT calibration accuracy is valid at the time of calibration only.





Sumbol	Description	Conditions	Resistance	Unit	
Symbol	Description	Conditions	C3, I3L	C4, I4	Unit
25-Ω R _S	Internal series termination without calibration (25- Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±40	±40	%
25-Ω R _S	Internal series termination without calibration (25- Ω setting)	$V_{CCIO} = 1.2 V$	±50	±50	%
50-Ω R _S	Internal series termination without calibration (50- Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±40	±40	%
50-Ω R _S	Internal series termination without calibration (50- Ω setting)	$V_{CCIO} = 1.2 V$	±50	±50	%
100-Ω R _D	Internal differential termination (100- Ω setting)	$V_{CCIO} = 2.5 V$	±25	±25	%

Figure 2-1: OCT Variation Without Re-Calibration for Arria V GZ Devices

$$\mathbf{R}_{\text{OCT}} = \mathbf{R}_{\text{SCAL}} \left(1 + \left(\frac{dR}{dT} \times \bigtriangleup T \right) \pm \left(\frac{dR}{dV} \times \bigtriangleup V \right) \right)$$

Notes:

1. The R_{oct} value shows the range of OCT resistance with the variation of temperature and V_{ccio} . 2. R_{scAL} is the OCT resistance value at power-up. 3. ΔT is the variation of temperature with respect to the temperature at power-up. 4. ΔV is the variation of voltage with respect to the V_{ccio} at power-up. 5. dR/dT is the percentage change of R_{scAL} with temperature. 6. dR/dV is the percentage change of R_{scAL} with voltage

6. dR/dV is the percentage change of R_{SCAL} with voltage.

Table 2-12: OCT Variation after Power-Up Calibration for Arria V GZ Devices

Valid for a V_{CCIO} range of \pm 5% and a temperature range of 0° to 85°C.





Symbol/Description	Conditions	Transceiver Speed Grade 2			Transo	Unit		
Symbol/Description	Conditions	Transceiver Speed Grade 2Transceiver Speed Grade 3UnitMinTypMaxMinTypMaxVCO post-divider $L = 2$ 8000—125008000—10312.5MbpsL = 44000—66004000—6600MbpsL = 8 (155)2000—33002000—3300Mbps						
	VCO post-divider L = 2	8000		12500	8000	_	10312.5	Mbps
Supported data rate range	L = 4	4000	_	6600	4000	_	6600	Mbps
	$L = 8^{(155)}$	2000	_	3300	2000	_	3300	Mbps
t _{pll_powerdown} ⁽¹⁵⁶⁾	_	1	—	_	1	_		μs
t _{pll_lock} ⁽¹⁵⁷⁾	_	_	_	10	_	_	10	μs

Related Information

- Arria V Device Overview For more information about device ordering codes.
- Transceiver Clocking in Arria V Devices For more information about clocking ATX PLLs.
- **Dynamic Reconfiguration in Arria V Devices** For more information about reconfiguring ATX PLLs.

Fractional PLL

Table 2-28: Fractional PLL Specifications for Arria V GZ Devices

Speed grades shown refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the *Arria V Device Overview*.



⁽¹⁵⁵⁾ This clock can be further divided by central or local clock dividers making it possible to use ATX PLL for data rates < 1 Gbps. For more information about ATX PLLs, refer to the Transceiver Clocking in Arria V Devices chapter and the Dynamic Reconfiguration in Arria V Devices chapter.

 $t_{pll_powerdown}$ is the PLL powerdown minimum pulse width.

⁽¹⁵⁷⁾ $t_{pll \ lock}$ is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.

Mode ⁽¹⁶⁴⁾	Transceiver	PMA Width	20	20	16	16	10	10	8	8
Mode	Speed Grade	PCS/Core Width	40	20	32	16	20	10	16	8
Dogistor	2	C3, I3L core speed grade	9.9	9	7.92	7.2	4.9	4.,5	3.92	3.6
icgistei	3	C4, I4 core speed grade	8.8	8.2	7.04	6.56	4.4	4.1	3.52	3.28

Related Information

Operating Conditions on page 2-1

10G PCS Data Rate

Table 2-31: 10G PCS Approximate Maximum Data Rate (Gbps) for Arria V GZ Devices

Mode ⁽¹⁶⁵⁾	Transceiver Speed Grade	PMA Width	64	40	40	40	32	32
Mode		PCS Width	64	66/67	50	40	64/66/67	32
FIFO	2	C3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88
	3	C4, I4 core speed grade	10.3125	10.3125	10.69	10.3125	9.92	9.92
Register	2	C3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88
	3	C4, I4 core speed grade	10.3125	10.3125	10.69	10.3125	9.92	9.92

⁽¹⁶⁴⁾ The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.



⁽¹⁶⁵⁾ The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

Sumbol	Conditions	C3, I3L				C4, I4		Unit
Symbol		Min	Тур	Max	Min	Тур	Max	Onic
	SERDES factor J = 3 to 10 (182), (183)	(184)	_	1250	(184)	_	1050	Mbps
True Differential I/O Standards - f _{HSDR} (data rate)	SERDES factor $J \ge 4$ LVDS TX with DPA (185), (186), (187), (188)	(184)		1600	(184)	_	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	(184)	—	(189)	(184)	_	(189)	Mbps
	SERDES factor J = 1, uses SDR Register	(184)	—	(189)	(184)		(189)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f _{HSDR} (data rate) (190)	SERDES factor J = 4 to 10 ⁽¹⁹¹⁾	(184)		840	(184)		840	Mbps

⁽¹⁸²⁾ If the receiver with DPA enabled and transmitter are using shared PLLs, the minimum data rate is 150 Mbps.

- ⁽¹⁸⁵⁾ Arria V GZ RX LVDS will need DPA. For Arria V GZ TX LVDS, the receiver side component must have DPA.
- Requires package skew compensation with PCB trace length. (186)
- (187)Do not mix single-ended I/O buffer within LVDS I/O bank.
- Chip-to-chip communication only with a maximum load of 5 pF. (188)
- ⁽¹⁸⁹⁾ The maximum ideal data rate is the SERDES factor (J) x the PLL maximum output frequency (fOUT) provided you can close the design timing and the signal integrity simulation is clean.
- ⁽¹⁹⁰⁾ You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine leftover timing margin.
- ⁽¹⁹¹⁾ When using True LVDS RX channels for emulated LVDS TX channel, only serialization factors 1 and 2 are supported.



⁽¹⁸³⁾ The F_{MAX} specification is based on the fast clock used for serial data. The interface F_{MAX} is also dependent on the parallel clock domain which is design dependent and requires timing analysis.

⁽¹⁸⁴⁾ The minimum specification depends on the clock source (for example, the PLL and clock pin) and the clock routing resource (global, regional, or local) that you use. The I/O differential buffer and input register do not have a minimum toggle rate.

2-50 Soft CDR Mode High-Speed I/O Specifications

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions ⁽²⁰¹⁾	Maximum
Darallel Papid I/O	00001111	2	128	640 data transitions
rataliei Kapid 1/0	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
Miscellaneous	01010101	8	32	640 data transitions

Soft CDR Mode High-Speed I/O Specifications

Table 2-44: High-Speed I/O Specifications for Arria V GZ Devices

When J = 3 to 10, use the serializer/deserializer (SERDES) block.

When J = 1 or 2, bypass the SERDES block.

Symbol	Conditions	C3, I3L			C4, I4			Unit	
Symbol		Min	Тур	Max	Min	Тур	Max	Unit	
Soft-CDR ppm tolerance	—	_	_	300	_	_	300	± ppm	





⁽²⁰¹⁾ This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

OCT Calibration Block Specifications

Table 2-51: OCT Calibration Block Specifications for Arria V GZ Devices

Symbol	Description	Min	Тур	Max	Unit
OCTUSRCLK	Clock required by the OCT calibration blocks	—	—	20	MHz
T _{OCTCAL}	Number of OCTUSRCLK clock cycles required for OCT R_S/R_T calibration		1000		Cycles
T _{OCTSHIFT}	Number of OCTUSRCLK clock cycles required for the OCT code to shift out	_	32	—	Cycles
T _{RS_RT}	Time required between the dyn_term_ctrl and oe signal transitions in a bidirectional I/O buffer to dynamically switch between OCT R_S and R_T (See the figure below.)		2.5		ns

Figure 2-6: Timing Diagram for oe and dyn_term_ctrl Signals





Symbol	Parameter	Minimum	Maximum	Unit
t _{CO}	DCLK falling edge to AS_DATA0/ASDO output	-	4	ns
t _{SU}	Data setup time before falling edge on DCLK	1.5		ns
t _H	Data hold time after falling edge on DCLK	0	—	ns
t _{CD2UM}	CONF_DONE high to user mode ⁽²¹⁶⁾	175	437	μs
t _{CD2CU}	CONF_DONE high to CLKUSR enabled	$4 \times \text{maximum DCLK}$ period	—	_
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t _{CD2CU} + (8576 × clkusr period)	_	_

Table 2-59: DCLK Frequency Specification in the AS Configuration Scheme

This applies to the DCLK frequency specification when using the internal oscillator as the configuration clock source.

The AS multi-device configuration scheme does not support ${\tt DCLK}$ frequency of 100 MHz.

Minimum	Typical	Maximum	Unit	
5.3	7.9	12.5	MHz	
10.6	15.7	25.0	MHz	
21.3	31.4	50.0	MHz	
42.6	62.9	100.0	MHz	

Related Information

- Passive Serial Configuration Timing on page 2-67
- Configuration, Design Security, and Remote System Upgrades in Arria V Devices





⁽²¹⁶⁾ To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on this pin, refer to the "Initialization" section of the *Configuration, Design Security, and Remote System Upgrades in Arria V Devices* chapter.

Related Information

- Configuration, Design Security, and Remote System Upgrades in Arria V Devices For more information about the reconfiguration input for the ALTREMOTE_UPDATE IP core, refer to the "User Watchdog Timer" section.
- Configuration, Design Security, and Remote System Upgrades in Arria V Devices For more information about the reset_timer input for the ALTREMOTE_UPDATE IP core, refer to the "Remote System Upgrade State Machine" section.

User Watchdog Internal Oscillator Frequency Specification

Table 2-65: User Watchdog Internal Oscillator Frequency Specifications

Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz

I/O Timing

Altera offers two ways to determine I/O timing—the Excel-based I/O Timing and the Quartus II Timing Analyzer.

Excel-based I/O timing provides pin timing performance for each device density and speed grade. The data is typically used prior to designing the FPGA to get an estimate of the timing budget as part of the link timing analysis.

The Quartus II Timing Analyzer provides a more accurate and precise I/O timing data based on the specifics of the design after you complete placeand-route.

Related Information

Arria V Devices Documentation page

For the Excel-based I/O Timing spreadsheet

Arria V GZ Device Datasheet

Altera Corporation



⁽²²⁶⁾ This is equivalent to strobing the reconfiguration input of the ALTREMOTE_UPDATE IP core high for the minimum timing specification. For more information, refer to the "Remote System Upgrade State Machine" section in the Configuration, Design Security, and Remote System Upgrades in Arria V Devices chapter.

⁽²²⁷⁾ This is equivalent to strobing the reset_timer input of the ALTREMOTE_UPDATE IP core high for the minimum timing specification. For more information, refer to the "User Watchdog Timer" section in the Configuration, Design Security, and Remote System Upgrades in Arria V Devices chapter.

Term	Definition						
R _L	Receiver differential input discrete resistor (external to the Arria V GZ device).						
SW (sampling window)	Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown:						
		Bit Time					
		0.5 x TCCS	RSKM	Sampling Window (SW)	RSKM	0.5 x TCCS	
Single-ended voltage referenced I/O standard	 The JEDEC standard for SSTL and HSTL I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: Single-Ended Voltage Referenced I/O Standard 						
		V _{0H}		V REF	Viн(DC Vil(DC)	V <u>ccio</u> VIH(AC) VIL(AC) VIL(AC)	

